E·XFL

Intel - EPM7128SQC100-15ES Datasheet



Welcome to E-XFL.COM

Understanding <u>Embedded - CPLDs (Complex</u> <u>Programmable Logic Devices)</u>

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixedfunction ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

Applications of Embedded - CPLDs

Details

Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	15 ns
Voltage Supply - Internal	4.75V ~ 5.25V
Number of Logic Elements/Blocks	8
Number of Macrocells	128
Number of Gates	2500
Number of I/O	84
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	100-BQFP
Supplier Device Package	100-PQFP (20x14)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epm7128sqc100-15es

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

The MAX 7000E devices—including the EPM7128E, EPM7160E, EPM7192E, and EPM7256E devices—have several enhanced features: additional global clocking, additional output enable controls, enhanced interconnect resources, fast input registers, and a programmable slew rate.

In-system programmable MAX 7000 devices—called MAX 7000S devices—include the EPM7032S, EPM7064S, EPM7128S, EPM7160S, EPM7192S, and EPM7256S devices. MAX 7000S devices have the enhanced features of MAX 7000E devices as well as JTAG BST circuitry in devices with 128 or more macrocells, ISP, and an open-drain output option. See Table 4.

Table 4. MAX 7000 Device Feat	ures		
Feature	EPM7032 EPM7064 EPM7096	All MAX 7000E Devices	All MAX 7000S Devices
ISP via JTAG interface			\checkmark
JTAG BST circuitry			✓(1)
Open-drain output option			\checkmark
Fast input registers		~	
Six global output enables		~	\checkmark
Two global clocks		~	
Slew-rate control		~	
MultiVolt interface (2)	\checkmark	~	\checkmark
Programmable register	\checkmark	~	
Parallel expanders	\checkmark	~	
Shared expanders	\checkmark	~	\checkmark
Power-saving mode	\checkmark	 	\checkmark
Security bit	\checkmark	 ✓ 	\checkmark
PCI-compliant devices available	\checkmark	 	

Notes:

(1) Available only in EPM7128S, EPM7160S, EPM7192S, and EPM7256S devices only.

(2) The MultiVolt I/O interface is not available in 44-pin packages.

The MAX 7000 architecture supports 100% TTL emulation and high-density integration of SSI, MSI, and LSI logic functions. The MAX 7000 architecture easily integrates multiple devices ranging from PALs, GALs, and 22V10s to MACH and pLSI devices. MAX 7000 devices are available in a wide range of packages, including PLCC, PGA, PQFP, RQFP, and TQFP packages. See Table 5.

Table 5. M.	Table 5. MAX 7000 Maximum User I/O PinsNote (1)											
Device	44- Pin PLCC	44- Pin PQFP	44- Pin TQFP	68- Pin PLCC	84- Pin PLCC	100- Pin PQFP	100- Pin TQFP	160- Pin PQFP	160- Pin PGA	192- Pin PGA	208- Pin PQFP	208- Pin RQFP
EPM7032	36	36	36									
EPM7032S	36		36									
EPM7064	36		36	52	68	68						
EPM7064S	36		36		68		68					
EPM7096				52	64	76						
EPM7128E					68	84		100				
EPM7128S					68	84	84 (2)	100				
EPM7160E					64	84		104				
EPM7160S					64		84 (2)	104				
EPM7192E								124	124			
EPM7192S								124				
EPM7256E								132 (2)		164		164
EPM7256S											164 (2)	164

Notes:

 When the JTAG interface in MAX 7000S devices is used for either boundary-scan testing or for ISP, four I/O pins become JTAG pins.

(2) Perform a complete thermal analysis before committing a design to this device package. For more information, see the *Operating Requirements for Altera Devices Data Sheet*.

MAX 7000 devices use CMOS EEPROM cells to implement logic functions. The user-configurable MAX 7000 architecture accommodates a variety of independent combinatorial and sequential logic functions. The devices can be reprogrammed for quick and efficient iterations during design development and debug cycles, and can be programmed and erased up to 100 times.

Each LAB is fed by the following signals:

- **3**6 signals from the PIA that are used for general logic inputs
- Global controls that are used for secondary register functions
- Direct input paths from I/O pins to the registers that are used for fast setup times for MAX 7000E and MAX 7000S devices

Macrocells

The MAX 7000 macrocell can be individually configured for either sequential or combinatorial logic operation. The macrocell consists of three functional blocks: the logic array, the product-term select matrix, and the programmable register. The macrocell of EPM7032, EPM7064, and EPM7096 devices is shown in Figure 3.

Figure 3. EPM7032, EPM7064 & EPM7096 Device Macrocell



Shareable Expanders

Each LAB has 16 shareable expanders that can be viewed as a pool of uncommitted single product terms (one from each macrocell) with inverted outputs that feed back into the logic array. Each shareable expander can be used and shared by any or all macrocells in the LAB to build complex logic functions. A small delay (t_{SEXP}) is incurred when shareable expanders are used. Figure 5 shows how shareable expanders can feed multiple macrocells.

Figure 5. Shareable Expanders



Shareable expanders can be shared by any or all macrocells in an LAB.

Parallel Expanders

Parallel expanders are unused product terms that can be allocated to a neighboring macrocell to implement fast, complex logic functions. Parallel expanders allow up to 20 product terms to directly feed the macrocell OR logic, with five product terms provided by the macrocell and 15 parallel expanders provided by neighboring macrocells in the LAB.

Programmable Interconnect Array

Logic is routed between LABs via the programmable interconnect array (PIA). This global bus is a programmable path that connects any signal source to any destination on the device. All MAX 7000 dedicated inputs, I/O pins, and macrocell outputs feed the PIA, which makes the signals available throughout the entire device. Only the signals required by each LAB are actually routed from the PIA into the LAB. Figure 7 shows how the PIA signals are routed into the LAB. An EEPROM cell controls one input to a 2-input AND gate, which selects a PIA signal to drive into the LAB.



While the routing delays of channel-based routing schemes in masked or FPGAs are cumulative, variable, and path-dependent, the MAX 7000 PIA has a fixed delay. The PIA thus eliminates skew between signals and makes timing performance easy to predict.

I/O Control Blocks

The I/O control block allows each I/O pin to be individually configured for input, output, or bidirectional operation. All I/O pins have a tri-state buffer that is individually controlled by one of the global output enable signals or directly connected to ground or V_{CC} . Figure 8 shows the I/O control block for the MAX 7000 family. The I/O control block of EPM7032, EPM7064, and EPM7096 devices has two global output enable signals that are driven by two dedicated active-low output enable pins (OE1 and OE2). The I/O control block of MAX 7000E and MAX 7000S devices has six global output enable signals that are driven by the true or complement of two output enable signals, a subset of the I/O pins, or a subset of the I/O macrocells.

The instruction register length of MAX 7000S devices is 10 bits. Tables 10 and 11 show the boundary-scan register length and device IDCODE information for MAX 7000S devices.

Table 10. MAX 7000S Boundary-Scan Register Length							
Device	Boundary-Scan Register Length						
EPM7032S	1 (1)						
EPM7064S	1 (1)						
EPM7128S	288						
EPM7160S	312						
EPM7192S	360						
EPM7256S	480						

Note:

 This device does not support JTAG boundary-scan testing. Selecting either the EXTEST or SAMPLE/PRELOAD instruction will select the one-bit bypass register.

Table 11. 32-Bit MAX 7000 Device IDCODE Note (1)											
Device		IDCODE (32 Bits)									
	Version (4 Bits)	Part Number (16 Bits)	Manufacturer's Identity (11 Bits)	1 (1 Bit) (2)							
EPM7032S	0000	0111 0000 0011 0010	00001101110	1							
EPM7064S	0000	0111 0000 0110 0100	00001101110	1							
EPM7128S	0000	0111 0001 0010 1000	00001101110	1							
EPM7160S	0000	0111 0001 0110 0000	00001101110	1							
EPM7192S	0000	0111 0001 1001 0010	00001101110	1							
EPM7256S	0000	0111 0010 0101 0110	00001101110	1							

Notes:

(1) The most significant bit (MSB) is on the left.

(2) The least significant bit (LSB) for all JTAG IDCODEs is 1.

Table 1	Table 15. MAX 7000 5.0-V Device DC Operating Conditions Note (9)									
Symbol	Parameter	Conditions	Min	Max	Unit					
V _{IH}	High-level input voltage		2.0	V _{CCINT} + 0.5	V					
V _{IL}	Low-level input voltage		-0.5 (8)	0.8	V					
V _{OH}	5.0-V high-level TTL output voltage	I_{OH} = -4 mA DC, V_{CCIO} = 4.75 V (10)	2.4		V					
	3.3-V high-level TTL output voltage	$I_{OH} = -4 \text{ mA DC}, V_{CCIO} = 3.00 \text{ V} (10)$	2.4		V					
	3.3-V high-level CMOS output voltage	$I_{OH} = -0.1 \text{ mA DC}, V_{CCIO} = 3.0 \text{ V} (10)$	V _{CCIO} – 0.2		V					
V _{OL}	5.0-V low-level TTL output voltage	I_{OL} = 12 mA DC, V_{CCIO} = 4.75 V (11)		0.45	V					
	3.3-V low-level TTL output voltage	I_{OL} = 12 mA DC, V_{CCIO} = 3.00 V (11)		0.45	V					
	3.3-V low-level CMOS output voltage	I _{OL} = 0.1 mA DC, V _{CCIO} = 3.0 V(11)		0.2	V					
II.	Leakage current of dedicated input pins	$V_{I} = -0.5$ to 5.5 V (11)	-10	10	μA					
I _{OZ}	I/O pin tri-state output off-state current	V _I = -0.5 to 5.5 V (11), (12)	-40	40	μA					

Table 16. MAX 7000 5.0-V Device Capacitance: EPM7032, EPM7064 & EPM7096 Devices						
Symbol	Parameter	Conditions	Min	Max	Unit	
CIN	Input pin capacitance	V _{IN} = 0 V, f = 1.0 MHz		12	pF	
C _{I/O}	I/O pin capacitance	V _{OUT} = 0 V, f = 1.0 MHz		12	pF	

Table 1	7. MAX 7000 5.0-V Device Capa	acitance: MAX 7000E Devices Not	e (13)		
Symbol	Parameter	Conditions	Min	Max	Unit
C _{IN}	Input pin capacitance	V _{IN} = 0 V, f = 1.0 MHz		15	pF
C _{I/O}	I/O pin capacitance	V _{OUT} = 0 V, f = 1.0 MHz		15	pF

Table 1	8. MAX 7000 5.0-V Device Capa	(13)			
Symbol	Parameter	Conditions	Min	Max	Unit
CIN	Dedicated input pin capacitance	V _{IN} = 0 V, f = 1.0 MHz		10	pF
C _{I/O}	I/O pin capacitance	V _{OUT} = 0 V, f = 1.0 MHz		10	pF

.

MAX 7000 Programmable Logic Device Family Data Sheet

Notes to tables:

- (1) See the Operating Requirements for Altera Devices Data Sheet.
- (2) Minimum DC input voltage on I/O pins is -0.5 V and on 4 dedicated input pins is -0.3 V. During transitions, the inputs may undershoot to -2.0 V or overshoot to 7.0 V for input currents less than 100 mA and periods shorter than 20 ns.
- (3) Numbers in parentheses are for industrial-temperature-range devices.
- (4) V_{CC} must rise monotonically.
- (5) The POR time for all 7000S devices does not exceed 300 μs. The sufficient V_{CCINT} voltage level for POR is 4.5 V. The device is fully initialized within the POR time after V_{CCINT} reaches the sufficient POR voltage level.
- (6) 3.3-V I/O operation is not available for 44-pin packages.
- (7) The V_{CCISP} parameter applies only to MAX 7000S devices.
- (8) During in-system programming, the minimum DC input voltage is -0.3 V.
- (9) These values are specified under the MAX 7000 recommended operating conditions in Table 14 on page 26.
- (10) The parameter is measured with 50% of the outputs each sourcing the specified current. The I_{OH} parameter refers to high-level TTL or CMOS output current.
- (11) The parameter is measured with 50% of the outputs each sinking the specified current. The I_{OL} parameter refers to low-level TTL, PCI, or CMOS output current.
- (12) When the JTAG interface is enabled in MAX 7000S devices, the input leakage current on the JTAG pins is typically -60 μA.
- (13) Capacitance is measured at 25° C and is sample-tested only. The OE1 pin has a maximum capacitance of 20 pF.

Figure 11 shows the typical output drive characteristics of MAX 7000 devices.

Figure 11. Output Drive Characteristics of 5.0-V MAX 7000 Devices



Timing Model

MAX 7000 device timing can be analyzed with the Altera software, with a variety of popular industry-standard EDA simulators and timing analyzers, or with the timing model shown in Figure 12. MAX 7000 devices have fixed internal delays that enable the designer to determine the worst-case timing of any design. The Altera software provides timing simulation, point-to-point delay prediction, and detailed timing analysis for a device-wide performance evaluation.

Figure 12. MAX 7000 Timing Model



Notes:

- (1) Only available in MAX 7000E and MAX 7000S devices.
- (2) Not available in 44-pin devices.

The timing characteristics of any signal path can be derived from the timing model and parameters of a particular device. External timing parameters, which represent pin-to-pin timing delays, can be calculated as the sum of internal parameters. Figure 13 shows the internal timing relationship of internal and external delay parameters.



For more infomration, see *Application Note 94* (Understanding MAX 7000 *Timing*).

Figure 13. Switching Waveforms



Symbol	Parameter	Conditions	Speed	Grade -6	Speed (Unit	
			Min	Max	Min	Max	
t _{IN}	Input pad and buffer delay			0.4		0.5	ns
t _{IO}	I/O input pad and buffer delay			0.4		0.5	ns
t _{FIN}	Fast input delay	(2)		0.8		1.0	ns
t _{SEXP}	Shared expander delay			3.5		4.0	ns
t _{PEXP}	Parallel expander delay			0.8		0.8	ns
t _{LAD}	Logic array delay			2.0		3.0	ns
t _{LAC}	Logic control array delay			2.0		3.0	ns
t _{IOE}	Internal output enable delay	(2)				2.0	ns
t _{OD1}	Output buffer and pad delay Slow slew rate = off, V _{CCIO} = 5.0 V	C1 = 35 pF		2.0		2.0	ns
t _{OD2}	Output buffer and pad delay Slow slew rate = off, V _{CCIO} = 3.3 V	C1 = 35 pF (7)		2.5		2.5	ns
t _{OD3}	Output buffer and pad delay Slow slew rate = on, V _{CCIO} = 5.0 V or 3.3 V	C1 = 35 pF (2)		7.0		7.0	ns
t _{ZX1}	Output buffer enable delay Slow slew rate = off, $V_{CCIO} = 5.0 \text{ V}$	C1 = 35 pF		4.0		4.0	ns
t _{ZX2}	Output buffer enable delay Slow slew rate = off, $V_{CCIO} = 3.3 \text{ V}$	C1 = 35 pF (7)		4.5		4.5	ns
t _{ZX3}	Output buffer enable delay Slow slew rate = on $V_{CCIO} = 5.0 V \text{ or } 3.3 V$	C1 = 35 pF (2)		9.0		9.0	ns
t _{XZ}	Output buffer disable delay	C1 = 5 pF		4.0		4.0	ns
t _{SU}	Register setup time		3.0		3.0		ns
t _H	Register hold time		1.5		2.0		ns
t _{FSU}	Register setup time of fast input	(2)	2.5		3.0		ns
t _{FH}	Register hold time of fast input	(2)	0.5		0.5		ns
t _{RD}	Register delay			0.8		1.0	ns
t _{COMB}	Combinatorial delay			0.8		1.0	ns
t _{IC}	Array clock delay			2.5		3.0	ns
t _{EN}	Register enable time			2.0		3.0	ns
t _{GLOB}	Global control delay			0.8		1.0	ns
t _{PRE}	Register preset time			2.0		2.0	ns
t _{CLR}	Register clear time			2.0		2.0	ns
t _{PIA}	PIA delay			0.8		1.0	ns
t _{I PA}	Low-power adder	(8)		10.0		10.0	ns

Symbol	Parameter	Conditions		Speed	Grade		Unit
			MAX 700	OE (-10P)	MAX 7000 (-10) MAX 7000E (-10)		
			Min	Max	Min	Max	
t _{PD1}	Input to non-registered output	C1 = 35 pF		10.0		10.0	ns
t _{PD2}	I/O input to non-registered output	C1 = 35 pF		10.0		10.0	ns
t _{SU}	Global clock setup time		7.0		8.0		ns
t _H	Global clock hold time		0.0		0.0		ns
t _{FSU}	Global clock setup time of fast input	(2)	3.0		3.0		ns
t _{FH}	Global clock hold time of fast input	(2)	0.5		0.5		ns
t _{CO1}	Global clock to output delay	C1 = 35 pF		5.0		5	ns
t _{CH}	Global clock high time		4.0		4.0		ns
t _{CL}	Global clock low time		4.0		4.0		ns
t _{ASU}	Array clock setup time		2.0		3.0		ns
t _{AH}	Array clock hold time		3.0		3.0		ns
t _{ACO1}	Array clock to output delay	C1 = 35 pF		10.0		10.0	ns
t _{ACH}	Array clock high time		4.0		4.0		ns
t _{ACL}	Array clock low time		4.0		4.0		ns
t _{CPPW}	Minimum pulse width for clear and preset	(3)	4.0		4.0		ns
t _{ODH}	Output data hold time after clock	C1 = 35 pF (4)	1.0		1.0		ns
t _{CNT}	Minimum global clock period			10.0		10.0	ns
f _{CNT}	Maximum internal global clock frequency	(5)	100.0		100.0		MHz
tACNT	Minimum array clock period			10.0		10.0	ns
f _{acnt}	Maximum internal array clock frequency	(5)	100.0		100.0		MHz
f _{MAX}	Maximum clock frequency	(6)	125.0		125.0		MHz

Symbol	Parameter	Conditions		Speed	Grade		Unit
			MAX 700	0E (-12P)	MAX 7000 (-12) MAX 7000E (-12)		
			Min	Max	Min	Max	
t _{PD1}	Input to non-registered output	C1 = 35 pF		12.0		12.0	ns
t _{PD2}	I/O input to non-registered output	C1 = 35 pF		12.0		12.0	ns
t _{SU}	Global clock setup time		7.0		10.0		ns
t _H	Global clock hold time		0.0		0.0		ns
t _{FSU}	Global clock setup time of fast input	(2)	3.0		3.0		ns
t _{FH}	Global clock hold time of fast input	(2)	0.0		0.0		ns
t _{CO1}	Global clock to output delay	C1 = 35 pF		6.0		6.0	ns
t _{CH}	Global clock high time		4.0		4.0		ns
t _{CL}	Global clock low time		4.0		4.0		ns
t _{ASU}	Array clock setup time		3.0		4.0		ns
t _{AH}	Array clock hold time		4.0		4.0		ns
t _{ACO1}	Array clock to output delay	C1 = 35 pF		12.0		12.0	ns
t _{ACH}	Array clock high time		5.0		5.0		ns
t _{ACL}	Array clock low time		5.0		5.0		ns
t _{CPPW}	Minimum pulse width for clear and preset	(3)	5.0		5.0		ns
t _{ODH}	Output data hold time after clock	C1 = 35 pF (4)	1.0		1.0		ns
t _{CNT}	Minimum global clock period			11.0		11.0	ns
f _{CNT}	Maximum internal global clock frequency	(5)	90.9		90.9		MHz
t _{ACNT}	Minimum array clock period			11.0		11.0	ns
f _{ACNT}	Maximum internal array clock frequency	(5)	90.9		90.9		MHz
f _{MAX}	Maximum clock frequency	(6)	125.0		125.0		MHz

Symbol	Parameter	Conditions	Speed Grade							
			-	15	-1	5T	-20			
			Min	Max	Min	Max	Min	Max		
t _{IN}	Input pad and buffer delay			2.0		2.0		3.0	ns	
t _{IO}	I/O input pad and buffer delay			2.0		2.0		3.0	ns	
t _{FIN}	Fast input delay	(2)		2.0		-		4.0	ns	
t _{SEXP}	Shared expander delay			8.0		10.0		9.0	ns	
t _{PEXP}	Parallel expander delay			1.0		1.0		2.0	ns	
t _{LAD}	Logic array delay			6.0		6.0		8.0	ns	
t _{LAC}	Logic control array delay			6.0		6.0		8.0	ns	
t _{IOE}	Internal output enable delay	(2)		3.0		-		4.0	ns	
t _{OD1}	Output buffer and pad delay Slow slew rate = off V _{CCIO} = 5.0 V	C1 = 35 pF		4.0		4.0		5.0	ns	
t _{OD2}	Output buffer and pad delay Slow slew rate = off $V_{CCIO} = 3.3 V$	C1 = 35 pF (7)		5.0		-		6.0	ns	
t _{OD3}	Output buffer and pad delay Slow slew rate = on $V_{CCIO} = 5.0 V \text{ or } 3.3 V$	C1 = 35 pF (2)		8.0		-		9.0	ns	
t _{ZX1}	Output buffer enable delay Slow slew rate = off $V_{CCIO} = 5.0 V$	C1 = 35 pF		6.0		6.0		10.0	ns	
t _{ZX2}	Output buffer enable delay Slow slew rate = off $V_{CCIO} = 3.3 V$	C1 = 35 pF (7)		7.0		-		11.0	ns	
t _{ZX3}	Output buffer enable delay Slow slew rate = on $V_{CCIO} = 5.0 V \text{ or } 3.3 V$	C1 = 35 pF (2)		10.0		-		14.0	ns	
t _{XZ}	Output buffer disable delay	C1 = 5 pF		6.0		6.0		10.0	ns	
t _{SU}	Register setup time		4.0		4.0		4.0		ns	
t _H	Register hold time		4.0		4.0		5.0		ns	
t _{FSU}	Register setup time of fast input	(2)	2.0		-		4.0		ns	
t _{FH}	Register hold time of fast input	(2)	2.0		-		3.0		ns	
t _{RD}	Register delay			1.0		1.0		1.0	ns	
t _{COMB}	Combinatorial delay			1.0		1.0		1.0	ns	
t _{IC}	Array clock delay			6.0		6.0		8.0	ns	
t _{EN}	Register enable time			6.0		6.0		8.0	ns	
t _{GLOB}	Global control delay			1.0		1.0		3.0	ns	
t _{PRE}	Register preset time			4.0		4.0		4.0	ns	
t _{CLR}	Register clear time			4.0		4.0		4.0	ns	
t _{PIA}	PIA delay			2.0		2.0		3.0	ns	
t _{LPA}	Low-power adder	(8)		13.0		15.0		15.0	ns	

Notes to tables:

- (1) These values are specified under the recommended operating conditions shown in Table 14. See Figure 13 for more information on switching waveforms.
- (2) This parameter applies to MAX 7000E devices only.
- (3) This minimum pulse width for preset and clear applies for both global clear and array controls. The t_{LPA} parameter must be added to this minimum width if the clear or reset signal incorporates the t_{LAD} parameter into the signal path.
- (4) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies for both global and array clocking.
- (5) These parameters are measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (6) The f_{MAX} values represent the highest frequency for pipelined data.
- (7) Operating conditions: $V_{CCIO} = 3.3 \text{ V} \pm 10\%$ for commercial and industrial use.
- (8) The t_{LPA} parameter must be added to the t_{LAD} , t_{LAC} , t_{IC} , t_{EN} , t_{SEXP} , t_{ACL} , and t_{CPPW} parameters for macrocells running in the low-power mode.

Tables 27 and 28 show the EPM7032S AC operating conditions.

Symbol	Parameter	Conditions	Speed Grade									
			-	5	-	-6		7	-	-10		
			Min	Max	Min	Max	Min	Max	Min	Max		
t _{PD1}	Input to non-registered output	C1 = 35 pF		5.0		6.0		7.5		10.0	ns	
t _{PD2}	I/O input to non-registered output	C1 = 35 pF		5.0		6.0		7.5		10.0	ns	
t _{SU}	Global clock setup time		2.9		4.0		5.0		7.0		ns	
t _H	Global clock hold time		0.0		0.0		0.0		0.0		ns	
t _{FSU}	Global clock setup time of fast input		2.5		2.5		2.5		3.0		ns	
t _{FH}	Global clock hold time of fast input		0.0		0.0		0.0		0.5		ns	
t _{CO1}	Global clock to output delay	C1 = 35 pF		3.2		3.5		4.3		5.0	ns	
t _{CH}	Global clock high time		2.0		2.5		3.0		4.0		ns	
t _{CL}	Global clock low time		2.0		2.5		3.0		4.0		ns	
t _{ASU}	Array clock setup time		0.7		0.9		1.1		2.0		ns	
t _{AH}	Array clock hold time		1.8		2.1		2.7		3.0		ns	
t _{ACO1}	Array clock to output delay	C1 = 35 pF		5.4		6.6		8.2		10.0	ns	
t _{ACH}	Array clock high time		2.5		2.5		3.0		4.0		ns	
t _{ACL}	Array clock low time		2.5		2.5		3.0		4.0		ns	
t _{CPPW}	Minimum pulse width for clear and preset	(2)	2.5		2.5		3.0		4.0		ns	
t _{ODH}	Output data hold time after clock	C1 = 35 pF (3)	1.0		1.0		1.0		1.0		ns	
t _{CNT}	Minimum global clock period			5.7		7.0		8.6		10.0	ns	
f _{CNT}	Maximum internal global clock frequency	(4)	175.4		142.9		116.3		100.0		MHz	
t ACNT	Minimum array clock period			5.7		7.0		8.6		10.0	ns	

Table 29. EPM7064S External Timing Parameters (Part 2 of 2) Note (1)												
Symbol	Parameter	Conditions				Speed	Grade	1			Unit	
			-	5	-6		-7		-10			
			Min	Max	Min	Max	Min	Max	Min	Max		
t _{ACO1}	Array clock to output delay	C1 = 35 pF		5.4		6.7		7.5		10.0	ns	
t _{ACH}	Array clock high time		2.5		2.5		3.0		4.0		ns	
t _{ACL}	Array clock low time		2.5		2.5		3.0		4.0		ns	
t _{CPPW}	Minimum pulse width for clear and preset	(2)	2.5		2.5		3.0		4.0		ns	
t _{ODH}	Output data hold time after clock	C1 = 35 pF (3)	1.0		1.0		1.0		1.0		ns	
t _{CNT}	Minimum global clock period			5.7		7.1		8.0		10.0	ns	
f _{CNT}	Maximum internal global clock frequency	(4)	175.4		140.8		125.0		100.0		MHz	
t _{ACNT}	Minimum array clock period			5.7		7.1		8.0		10.0	ns	
f _{ACNT}	Maximum internal array clock frequency	(4)	175.4		140.8		125.0		100.0		MHz	
f _{MAX}	Maximum clock frequency	(5)	250.0		200.0		166.7		125.0		MHz	

Г

 Table 30. EPM7064S Internal Timing Parameters (Part 1 of 2)

 Note (1)

Symbol	Parameter	Conditions				Speed	Grade)			Unit
			-	5	-	6	-7		-10		-
			Min	Max	Min	Max	Min	Max	Min	Max	
t _{IN}	Input pad and buffer delay			0.2		0.2		0.5		0.5	ns
t _{IO}	I/O input pad and buffer delay			0.2		0.2		0.5		0.5	ns
t _{FIN}	Fast input delay			2.2		2.6		1.0		1.0	ns
t _{SEXP}	Shared expander delay			3.1		3.8		4.0		5.0	ns
t _{PEXP}	Parallel expander delay			0.9		1.1		0.8		0.8	ns
t _{LAD}	Logic array delay			2.6		3.2		3.0		5.0	ns
t _{LAC}	Logic control array delay			2.5		3.2		3.0		5.0	ns
t _{IOE}	Internal output enable delay			0.7		0.8		2.0		2.0	ns
t _{OD1}	Output buffer and pad delay	C1 = 35 pF		0.2		0.3		2.0		1.5	ns
t _{OD2}	Output buffer and pad delay	C1 = 35 pF (6)		0.7		0.8		2.5		2.0	ns
t _{OD3}	Output buffer and pad delay	C1 = 35 pF		5.2		5.3		7.0		5.5	ns
t _{ZX1}	Output buffer enable delay	C1 = 35 pF		4.0		4.0		4.0		5.0	ns
t _{ZX2}	Output buffer enable delay	C1 = 35 pF (6)		4.5		4.5		4.5		5.5	ns
t _{ZX3}	Output buffer enable delay	C1 = 35 pF		9.0		9.0		9.0		9.0	ns
t _{XZ}	Output buffer disable delay	C1 = 5 pF		4.0		4.0		4.0		5.0	ns
t _{SU}	Register setup time		0.8		1.0		3.0		2.0		ns
t _H	Register hold time		1.7		2.0		2.0		3.0		ns

Symbol	Parameter	Conditions				Speed	Grade)			Unit		
			-	6	-	-7		-7		-10		-15	
			Min	Max	Min	Max	Min	Max	Min	Max			
t _{PD1}	Input to non-registered output	C1 = 35 pF		6.0		7.5		10.0		15.0	ns		
t _{PD2}	I/O input to non-registered output	C1 = 35 pF		6.0		7.5		10.0		15.0	ns		
t _{SU}	Global clock setup time		3.4		6.0		7.0		11.0		ns		
t _H	Global clock hold time		0.0		0.0		0.0		0.0		ns		
t _{FSU}	Global clock setup time of fast input		2.5		3.0		3.0		3.0		ns		
t _{FH}	Global clock hold time of fast input		0.0		0.5		0.5		0.0		ns		
t _{CO1}	Global clock to output delay	C1 = 35 pF		4.0		4.5		5.0		8.0	ns		
t _{CH}	Global clock high time		3.0		3.0		4.0		5.0		ns		
t _{CL}	Global clock low time		3.0		3.0		4.0		5.0		ns		
t _{ASU}	Array clock setup time		0.9		3.0		2.0		4.0		ns		
t _{AH}	Array clock hold time		1.8		2.0		5.0		4.0		ns		
t _{ACO1}	Array clock to output delay	C1 = 35 pF		6.5		7.5		10.0		15.0	ns		
t _{ACH}	Array clock high time		3.0		3.0		4.0		6.0		ns		
t _{ACL}	Array clock low time		3.0		3.0		4.0		6.0		ns		
t _{CPPW}	Minimum pulse width for clear and preset	(2)	3.0		3.0		4.0		6.0		ns		
t _{odh}	Output data hold time after clock	C1 = 35 pF (3)	1.0		1.0		1.0		1.0		ns		
t _{CNT}	Minimum global clock period			6.8		8.0		10.0		13.0	ns		
f _{CNT}	Maximum internal global clock frequency	(4)	147.1		125.0		100.0		76.9		MHz		
t _{ACNT}	Minimum array clock period			6.8		8.0		10.0		13.0	ns		
f _{ACNT}	Maximum internal array clock frequency	(4)	147.1		125.0		100.0		76.9		MHz		
f _{MAX}	Maximum clock frequency	(5)	166.7		166.7		125.0		100.0		MHz		

Tables 31 and 32 show the EPM7128S AC operating conditions.

٦

Г

Figures 16 through 22 show the package pin-out diagrams for MAX 7000 devices.

Figure 16. 44-Pin Package Pin-Out Diagram

Package outlines not drawn to scale.



Notes:

- (1) The pin functions shown in parenthesis are only available in MAX 7000E and MAX 7000S devices.
- (2) JTAG ports are available in MAX 7000S devices only.

Figure 21. 192-Pin Package Pin-Out Diagram

Package outline not drawn to scale.



Figure 22. 208-Pin Package Pin-Out Diagram

Package outline not drawn to scale.



Revision History

The information contained in the *MAX 7000 Programmable Logic Device Family Data Sheet* version 6.7 supersedes information published in previous versions. The following changes were made in the *MAX 7000 Programmable Logic Device Family Data Sheet* version 6.7:

Version 6.7

The following changes were made in the *MAX* 7000 *Programmable Logic Device Family Data Sheet* version 6.7:

Reference to AN 88: Using the Jam Language for ISP & ICR via an Embedded Processor has been replaced by AN 122: Using Jam STAPL for ISP & ICR via an Embedded Processor.

Version 6.6

The following changes were made in the *MAX* 7000 *Programmable Logic Device Family Data Sheet* version 6.6:

- Added Tables 6 through 8.
- Added "Programming Sequence" section on page 17 and "Programming Times" section on page 18.

Version 6.5

The following changes were made in the *MAX* 7000 *Programmable Logic Device Family Data Sheet* version 6.5:

Updated text on page 16.

Version 6.4

The following changes were made in the *MAX* 7000 Programmable Logic Device Family Data Sheet version 6.4:

Added Note (5) on page 28.

Version 6.3

The following changes were made in the *MAX* 7000 *Programmable Logic Device Family Data Sheet* version 6.3:

 Updated the "Open-Drain Output Option (MAX 7000S Devices Only)" section on page 20.